



INVITATION

to Seminar: "Thin Film Measurement"

Time: June 25, 2013

Location: Radisson Blu Hotel Dortmund
An der Buschmuehle 1, 44139 Dortmund / Germany

Dear Sirs and Madams,

SENTECH organizes a seminar on:

"Thin Film Measurement"

The seminar focuses on optical methods and applications for thin film analysis. Principles of spectroscopic ellipsometry, reflectometry and transmission measurements are presented. Contributions from experts cover the analysis of new materials, solar cells and nanotechnology with a special focus on industrial quality control.

We are glad to present an attractive program on "Thin Film Measurement" with experts from various research areas. The seminar program and the registration form are attached to this invitation.

Please use the attached form to register as soon as possible, as the number of participants is limited to 30. The participation is free of charge.

You can send us your registration

via e-mail: sales@sentech.de or

via fax: +49 89 897 9607-22

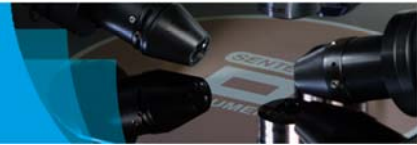
For further questions please contact us under: +49 89 897 9607-0.

Looking forward to meet you at our seminar in Dortmund.

Best regards

Your

SENTECH Team



Seminar

“Thin Film Measurement”

June 25, 2013

in Dortmund / Germany

Radisson Blu Hotel Dortmund

An der Buschmuehle 1

44139 Dortmund / Germany

Program

Introduction to ellipsometry

09.00 Introduction to ellipsometry

Uwe Richter, SENTECH Instruments GmbH, Berlin

09.30 The SENTECH ellipsometers and SpectraRay/3 software

Adrian Blümich, SENTECH Instruments GmbH, Berlin

Ellipsometry and materials research

10.00 Ellipsometric analysis of graphene films

Sven Peters, SENTECH Instruments GmbH, Berlin

10.30 Coffee break and discussion

10.45 Film metrology and its challenges at IMEC

Tae-Gon Kim, IMEC, Leuven / Belgium

Ellipsometry and industrial quality control

11.15 Optical measurements for quality control in thin film solar cell manufacturing

Adrian Blümich, Uwe Richter, SENTECH Instruments GmbH, Berlin

11.45 Standardized system integration for optimization of the quality assurance

Michael Jacob, AIS Automation Dresden GmbH, Dresden

12.15 Lunch break and discussion

Vibrational spectroscopy and IR ellipsometry

13.30 Infrared spectroscopic characterization of low temperature Si₂N₃ films using the SENDIRA spectroscopic ellipsometer

Bernd Gruska, SENTECH Instruments GmbH, Berlin

14.00 IR ellipsometry - a new sampling technique in thin film analysis and nanotechnologies

Andreas Hertwig, BAM, Berlin

14.30 Coffee break and discussion

Ellipsometry and scatterometry

14.45 Ellipsometric measurements on periodic nanostructures

Joerg Bischoff, Osiris Optical Engineering, Ilmenau

15.15 Demonstration of SENDIRA and SENpro

16.00 End of seminar



Erfolg
durch Leistung

SENTECH
Gesellschaft für Sensortechnik mbH

Konrad-Zuse-Bogen 13
82152 Krailling, Germany
Telefon: +49/89/ 8979607 - 0
Fax: +49/89/ 8979607 - 22
E-Mail: sales@sentech.de
Website: www.sentech-sales.de

Please send this form to:

SENTECH GmbH

Fax: +49 (0)89 8979607 22

E-Mail: sales@sentech.de

Title:	First Name:	Name:
Company:		
Dept.:		
Street:		ZIP Code + City:
Phone:		Fax:
E-Mail:		

SEMINAR REGISTRATION

<input type="checkbox"/>	Yes	I hereby register to the SEMINAR: "Thin Film Measurement" in Dortmund at June 25, 2013
..... Place, date	 Signature